

**Notice of References Cited**

Application/Control No.

10/584,316

Applicant(s)/Patent Under  
Reexamination  
OKI ET AL.

Examiner

WILLIAM K. CHEUNG

Art Unit

1796

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0128165	09-2002	Baker et al.	510/309
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	EP 0 297 673	01-1989	Europe	Baeck et al.	---
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	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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